Application No.: 10/568,229

Filing Date: February 14, 2006

LISTING OF CLAIMS

No claims are amended herein.

 (Original) A quaternary or higher group IB-IIIA-VIA alloy having the general formula (I):

$$A(B_{1-x}C_x)(D_{1-y}E_y)_2.....(I)$$

wherein:

A is a group IB element;

B is a group IIIA element;

C is a group IIIA element, which is different to B;

D is a first group VIA element (hereinafter referred to as VIA_I);

E is a second group VIA element (hereinafter referred to as VIA2); and

each of x and y independently are from 0 to 1, provided that both x and y are not zero at the same time;

and the alloy being characterized by an x-ray diffraction pattern (XRD) having a main [112] peak at a 20 angle ($2\theta_{(112)}$) of from 26° to 28° for Cu radiation at 40kV, wherein a glancing incidence x ray diffraction pattern (GIXRD) for a glancing angle of from 0.2° to 10° reflects an absolute shift in the $2\theta_{(112)}$ angle of less than 0.06°.

- (Original) The alloy of Claim 1, wherein the alloy has a crystal structure comprising a lattice of unit cells, wherein all crystallographic planes of the unit cells show a variance in d-spacing of less than 0.01Å.
- (Original) The alloy of claim 1, wherein the element concentration of elements A,
 B, C, D, and E, as characterized by XPS depth profiling, is substantially uniform through the alloy.
- 4. (Original) The alloy of claim 1, wherein A is Cu, B is In, C is Ga, D is Se and E is S, the alloy having a formula (II):

$$Cu(In_{1-x}Ga_x)(Se_{1-y}S_y)_2 \dots (II)$$

5. (Original) The alloy of claim 4, wherein x is from 0.25 to 0.3 and y is from 0.05 to 0.8.

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(Original) The alloy of claim 4, wherein the x-ray diffraction pattern (XRD) has a
main [112] peak at a 20 angle (20₍₁₁₂₎) of from 26.9° to 28° for Cu radiation at 40kV, taken at a
d-spacing of from 3.3117Å to 3.1840Å.

- 7. (Original) The alloy of claim 4, wherein the GIXRD for a glancing angle of from 0.2° to 10° reflects an absolute shift in the $2\theta_{(112)}$ angle of less than 0.01° .
- (Original) The alloy of claim 4, wherein the alloy has a crystal structure comprising a lattice of unit cells, wherein all crystallographic planes of the unit cells show a variance in d-spacing of less than 0.001 Å.
- 9. (Original) The alloy of claim 6, wherein the main [112] peak is from a 2θ angle of from 27.0° to 27.5° .
- (Original) The alloy of claim 6, wherein the main [112] peak is substantially symmetrical.
- 11. (Original) The alloy of claim 4, wherein the alloy has a band gap that can be shifted from 1 eV to $2.4~{\rm eV}$.
- 12. (Original) The alloy of claim 11, wherein the alloy has a band gap that can be shifted from 1.1 eV to 1.5 eV.
- 13. (Original) The alloy of claim 4, wherein the S content, as expressed by the molar ratio of $\frac{S}{(S+Se)}$, is from 0.05 to 0.7.
- 14. (Withdrawn) The alloy of claim 1, wherein A is Cu, B is In, C is Ga, D is Se and y= 0, the alloy having the general formula (III)

$$Cu(In_{1-x}Ga_x)Se_2$$
 (III)

- 15. (Withdrawn) The alloy of claim 14, wherein x is from 0.25 and 0.3.
- 16. (Withdrawn) The alloy of claim 14, wherein the alloy has a crystal structure comprising a lattice of unit cells, wherein all crystallographic planes of the unit cells show a variance in d-spacing of less than 0.006Å.
- 17. (Withdrawn) The alloy of claim 14, wherein the x-ray diffraction pattern (XRD) has a main [112] peak at a 2θ angle (2θ₍₁₁₂₎) of from 26.80° to 27.0° for Cu radiation at 40kV, taken at a d-spacing of from 3.3236Å to 3.2990Å.

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18. (Withdrawn) The alloy of claim 14, wherein the GIXRD for a glancing angle of from 0.2° to 10° reflects an absolute shift in the $2\theta_{1120}$ angle of less than 0.05°.

- (Withdrawn) The alloy of claim 17, wherein the main (112] peak lies from a 20 angle of from 26.85° to 26.9°.
- (Withdrawn) The alloy of claim 17, wherein the main (112] peak is substantially symmetrical.
- (Withdrawn) The alloy of claim 14, wherein the alloy has a band gap which can be shifted from 1.1 eV to 1.2 eV.
- (Withdrawn) The alloy of claim 21, wherein the alloy has a band gap which can be shifted from 1.15 eV to 1.18 eV.
- 23. (Withdrawn) The alloy of claim 14, wherein the Ga content, as expressed by the molar ratio of $\frac{Ga}{(Ga+In)}$ is from 0.25 to 0.3.
- 24. (Withdrawn) The alloy of claim 1, wherein A is Cu, B is In, D is Se, E is S and X = 0 and has the general formula (IV):

$$CuIn(Se_{1-y}S_y)_2 \dots (IV)$$

- 25. (Withdrawn) The alloy of claim 24, wherein y is from 0.1 and 0.5.
- 26. (Withdrawn) The alloy of claim 24, wherein the alloy has a crystal structure comprising a lattice of unit cells, wherein all crystallographic planes of the unit cells show a variance in d-spacing of less than 0.007Å.
- 27. (Withdrawn) The alloy of claim 24, wherein the x-ray diffraction pattern (XRD) has a main (112] peak at a 2θ angle (2θ₍₁₁₂₎) of from 26.80° to 27.3° for Cu radiation at 40kV, taken at a d-spacing of from 3.3236Å to 3.2640Å.
- 28. (Withdrawn) The alloy of claim 24, wherein the GIXRD for a glancing angle of from 0.2° to 10° reflects an absolute shift in the $2\theta_{(112)}$ angle of less than 0.06°.
- (Withdrawn) The alloy of claim 27, wherein the main (112] peak lies from a 20 angle of from 27.0° to 27.2°.
- (Withdrawn) The alloy of claim 24, wherein the alloy has a band gap which can be shifted from 1.05 eV to 1.23 eV.

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31. (Withdrawn) The alloy of claim 30, wherein the alloy has a band gap which can be shifted from 1.15 eV to 1.20 eV.

- 32. (Withdrawn) The alloy of claim 24, wherein the S content, as expressed by the ratio of $\frac{S}{(S+Se)}$ lies from 0.1 and 0.5.
 - (Withdrawn) A semiconductor film comprising a film of an alloy of claim 1.
- 34. (Withdrawn) The semiconductor film of claim 33, wherein the alloy of claim 1 is deposited onto a substrate which serves as a support for the alloy.
- (Withdrawn) The semiconductor film according to claim 33, wherein the alloy is in the form of a film having a thickness of 1.5 to 2.0
 µm.
- (Withdrawn) A photovoltaic cell including a semiconductor film of an alloy of claim 1.
- 37. (Withdrawn) The photovoltaic cell according to claim 36, wherein the photovoltaic cell has a conversion efficiency of from 8 to 15%.